

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				2 *****
				3 *
				4 * Zvector E6 instruction tests for VRI-f encoded:
				5 *
				6 * E670 VPKZR - VECTOR PACK ZONED REGISTER
				7 *
				8 * James Wekel June 2024
				9 *****
				10
				11 *****
				12 *
				13 * basic instruction tests
				14 *
				15 *****
				16 * This program tests proper functioning of the z/arch E6 VRI-f vector
				17 * pack zoned register instruction. Exceptions are not tested.
				18 *
				19 * PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
				20 * obvious coding errors. None of the tests are thorough. They are
				21 * NOT designed to test all aspects of any of the instructions.
				22 *
				23 *****
				24 *
				25 * *Testcase VECTOR E6 VPKZR: packed zoned register instruction
				26 * *
				27 * * Zvector E6 tests for VRI-f encoded pack instructions:
				28 * *
				29 * * E670 VPKZR - VECTOR PACK ZONED REGISTER VPKZR
				30 * *
				31 * * # -----
				32 * * # This tests only the basic function of the instruction.
				33 * * # Exceptions are NOT tested.
				34 * * # -----
				35 * *
				36 * main size 2
				37 * numcpu 1
				38 * sysclear
				39 * archlvl z/Arch
				40 *
				41 * loadcore "\$(testpath)/zvector-e6-06-VPKZR.core" 0x0
				42 *
				43 * diag8cmd enable # (needed for messages to Hercules console)
				44 * runtest 2
				45 * diag8cmd disable # (reset back to default)
				46 *
				47 * *Done
				48 *****

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				50 *****
				51 * FCHECK Macro - Is a Facility Bit set?
				52 *
				53 * If the facility bit is NOT set, an message is issued and
				54 * the test is skipped.
				55 *
				56 * Fcheck uses R0, R1 and R2
				57 *
				58 * eg. FCHECK 134, 'vector-packed-decimal'
				59 *****
				60 MACRO
				61 FCHECK &BITNO, &NOTSETMSG
				62 . * &BITNO : facility bit number to check
				63 . * &NOTSETMSG : 'facility name'
				64 LCLA &FBBYTE Facility bit in Byte
				65 LCLA &FBBIT Facility bit within Byte
				66
				67 LCLA &L(8)
				68 &L(1) SetA 128, 64, 32, 16, 8, 4, 2, 1 bit positions within byte
				69
				70 &FBBYTE SETA &BITNO/8
				71 &FBBIT SETA &L((&BITNO-(&FBBYTE*8))+1)
				72 . * MNOTE 0, 'checking Bit=&BITNO: FBBYTE=&FBBYTE, FBBIT=&FBBIT'
				73
				74 B X&SYSNDX
				75 * Fcheck data area
				76 * skip messgae
				77 SKT&SYSNDX DC C' Skipping tests: '
				78 DC C&NOTSETMSG
				79 DC C' facility (bit &BITNO) is not installed.'
				80 SKL&SYSNDX EQU *-SKT&SYSNDX
				81 * facility bits
				82 DS FD gap
				83 FB&SYSNDX DS 4FD
				84 DS FD gap
				85 *
				86 X&SYSNDX EQU *
				87 LA R0, ((X&SYSNDX- FB&SYSNDX)/8)-1
				88 STFLE FB&SYSNDX get facility bits
				89
				90 XGR R0, R0
				91 IC R0, FB&SYSNDX+&FBBYTE get fbit byte
				92 N R0, =F' &FBBIT' is bit set?
				93 BNZ XC&SYSNDX
				94 *
				95 * facility bit not set, issue message and exit
				96 *
				97 LA R0, SKL&SYSNDX message length
				98 LA R1, SKT&SYSNDX message address
				99 BAL R2, MSG
				100
				101 B EOJ
				102 XC&SYSNDX EQU *
				103 MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				125 *****	
				126 *	The actual "ZVE6TST" program itself...
				127 *****	
				128 *	
				129 *	Architecture Mode: z/Arch
				130 *	Register Usage:
				131 *	
				132 *	R0 (work)
				133 *	R1-4 (work)
				134 *	R5 Testing control table - current test base
				135 *	R6- R7 (work)
				136 *	R8 First base register
				137 *	R9 Second base register
				138 *	R10 Third base register
				139 *	R11 E6TEST call return
				140 *	R12 E6TESTS register
				141 *	R13 (work)
				142 *	R14 Subroutine call
				143 *	R15 Secondary Subroutine call or work
				144 *	
				145 *****	
00000200		00000200		147	USING BEGIN, R8 FIRST Base Register
00000200		00001200		148	USING BEGIN+4096, R9 SECOND Base Register
00000200		00002200		149	USING BEGIN+8192, R10 THIRD Base Register
00000200	0580			151	BEGIN BALR R8, 0 Initalize FIRST base register
00000202	0680			152	BCTR R8, 0 Initalize FIRST base register
00000204	0680			153	BCTR R8, 0 Initalize FIRST base register
00000206	4190 8800		00000800	155	LA R9, 2048(, R8) Initalize SECOND base register
0000020A	4190 9800		00000800	156	LA R9, 2048(, R9) Initalize SECOND base register
0000020E	41A0 9800		00000800	158	LA R10, 2048(, R9) Initalize THIRD base register
00000212	41A0 A800		00000800	159	LA R10, 2048(, R10) Initalize THIRD base register
				160	
00000216	B600 8374		00000574	161	STCTL R0, R0, CTLR0 Store CRO to enable AFP
0000021A	9604 8375		00000575	162	OI CTLR0+1, X' 04' Turn on AFP bit
0000021E	9602 8375		00000575	163	OI CTLR0+1, X' 02' Turn on Vector bit
00000222	B700 8374		00000574	164	LCTL R0, R0, CTLR0 Reload updated CRO
				165	
				166 *****	
				167 *	Is vector-packed-decimal-enhancement facility 2 installed (bit 192)
				168 *****	
				169	
00000226	47F0 80C8		000002C8	170	FCHECK 192, 'vector-packed-decimal-enhancement facility 2'
				171+	B X0001
				172+*	Fcheck data area
				173+*	skip messgae
0000022A	40404040 40404040			174+SKT0001	DC C' Skipping tests: '
00000244	A58583A3 96996097			175+	DC C' vector-packed-decimal-enhancement facility 2'
00000270	40868183 899389A3			176+	DC C' facility (bit 192) is not installed.'
		0000006B 00000001		177+SKL0001	EQU *-SKT0001
				178+*	facility bits
00000298	00000000 00000000			179+	DS FD gap
000002A0	00000000 00000000			180+FB0001	DS 4FD

LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						235	*****
						236	* cc was not as expected
						237	*****
00000340	E310	0001	0082	00000340	00000001	238	CCMSG EQU *
00000346	E310	5008	0076		00000001	239	XG R1, R1
0000034C	5410	8384			00000008	240	LB R1, M5 M5 has CS bit
00000350	4780	8124			00000584	241	N R1, =F' 1' get CS (CC set) bit
					00000324	242	BZ TESTREST ignore if not set
						243	*
						244	* extract CC extracted PSW
						245	*
00000354	5810	8EE8			000010E8	246	L R1, CCPSW
00000358	8810	000C			0000000C	247	SRL R1, 12
0000035C	5410	8388			00000588	248	N R1, =XL4' 3'
00000360	4210	8EF0			000010F0	249	STC R1, CCFOUND save cc
						250	*
						251	* FILL IN MESSAGE
						252	*
00000364	4820	5004			00000004	253	LH R2, TNUM get test number and convert
00000368	4E20	8ED5			000010D5	254	CVD R2, DECNUM
0000036C	D211	8EBF	8EA9	000010BF	000010A9	255	MVC PRT3, EDIT
00000372	DE11	8EBF	8ED5	000010BF	000010D5	256	ED PRT3, DECNUM
00000378	D202	8E64	8ECC	00001064	000010CC	257	MVC CCPRTNUM(3), PRT3+13 fill in message with test #
						258	
0000037E	D207	8E81	5014	00001081	00000014	259	MVC CCPRTNAME, OPNAME fill in message with instruction
						260	
00000384	B982	0022				261	XGR R2, R2 get CC as U8
00000388	4320	5009			00000009	262	IC R2, CC
0000038C	4E20	8ED5			000010D5	263	CVD R2, DECNUM and convert
00000390	D211	8EBF	8EA9	000010BF	000010A9	264	MVC PRT3, EDIT
00000396	DE11	8EBF	8ED5	000010BF	000010D5	265	ED PRT3, DECNUM
0000039C	D200	8E97	8ECE	00001097	000010CE	266	MVC CCPRTEXP(1), PRT3+15 fill in message with CC field
						267	
000003A2	B982	0022				268	XGR R2, R2 get CCFOUND as U8
000003A6	4320	8EF0			000010F0	269	IC R2, CCFOUND
000003AA	4E20	8ED5			000010D5	270	CVD R2, DECNUM and convert
000003AE	D211	8EBF	8EA9	000010BF	000010A9	271	MVC PRT3, EDIT
000003B4	DE11	8EBF	8ED5	000010BF	000010D5	272	ED PRT3, DECNUM
000003BA	D200	8EA7	8ECE	000010A7	000010CE	273	MVC CCPRTGOT(1), PRT3+15 fill in message with ccfound
						274	
000003C0	4100	0055			00000055	275	LA R0, CCPRTLNG message length
000003C4	4110	8E54			00001054	276	LA R1, CCPRTLNE messagfe address
000003C8	45F0	8256			00000456	277	BAL R15, RPTERROR
						278	
000003CC	47F0	8238			00000438	279	B FAILCONT

LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						281 *****	
						282 * result not as expected:	
						283 * issue message with test number, instruction under test	
						284 * and instruction m3	
						285 *****	
				000003D0	00000001	286 FAILMSG EQU *	
000003D0	4820	5004			00000004	287 LH R2, TNUM	get test number and convert
000003D4	4E20	8ED5			000010D5	288 CVD R2, DECNUM	
000003D8	D211	8EBF 8EA9		000010BF	000010A9	289 MWC PRT3, EDIT	
000003DE	DE11	8EBF 8ED5		000010BF	000010D5	290 ED PRT3, DECNUM	
000003E4	D202	8E18 8ECC		00001018	000010CC	291 MWC PRTNUM(3), PRT3+13	fill in message with test #
						292	
000003EA	D207	8E33 5014		00001033	00000014	293 MWC PRTNAME, OPNAME	fill in message with instruction
						294	
000003F0	B982	0022				295 XGR R2, R2	get i4 as U8
000003F4	4320	5007			00000007	296 IC R2, I4	
000003F8	4E20	8ED5			000010D5	297 CVD R2, DECNUM	and convert
000003FC	D211	8EBF 8EA9		000010BF	000010A9	298 MWC PRT3, EDIT	
00000402	DE11	8EBF 8ED5		000010BF	000010D5	299 ED PRT3, DECNUM	
00000408	D202	8E44 8ECC		00001044	000010CC	300 MWC PRTI4(3), PRT3+13	fill in message with i4 field
						301	
0000040E	B982	0022				302 XGR R2, R2	get m5 as U8
00000412	4320	5008			00000008	303 IC R2, M5	and convert
00000416	4E20	8ED5			000010D5	304 CVD R2, DECNUM	
0000041A	D211	8EBF 8EA9		000010BF	000010A9	305 MWC PRT3, EDIT	
00000420	DE11	8EBF 8ED5		000010BF	000010D5	306 ED PRT3, DECNUM	
00000426	D201	8E51 8ECD		00001051	000010CD	307 MWC PRTM5(2), PRT3+14	fill in message with m5 field
						308	
0000042C	4100	004C			0000004C	309 LA R0, PRTLNG	message length
00000430	4110	8E08			00001008	310 LA R1, PRTLNE	messagfe address
00000434	45F0	8256			00000456	311 BAL R15, RPTERROR	
						313 *****	
						314 * continue after a failed test	
						315 *****	
				00000438	00000001	316 FAILCONT EQU *	
00000438	5800	8384			00000584	317 L R0, =F' 1'	set GLOBAL failed test indicator
0000043C	5000	8E00			00001000	318 ST R0, FAILED	
						319	
00000440	41C0	C004			00000004	320 LA R12, 4(0, R12)	next test address
00000444	47F0	80F4			000002F4	321 B NEXTE6	
						323 *****	
						324 * end of testing; set ending psw	
						325 *****	
				00000448	00000001	326 ENDTEST EQU *	
00000448	5810	8E00			00001000	327 L R1, FAILED	did a test fail?
0000044C	1211					328 LTR R1, R1	
0000044E	4780	8358			00000558	329 BZ EOJ	No, exit
00000452	47F0	8370			00000570	330 B FAILTEST	Yes, exit with BAD PSW

[illegible]

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				395	*****
				396	* Normal completion or Abnormal termination PSWs
				397	*****
00000548	00020001 80000000			399 E0JPSW DC	OD' 0' , X' 0002000180000000' , AD(0)
00000558	B2B2 8348		00000548	401 E0J LPSWE E0JPSW	Normal completion
00000560	00020001 80000000			403 FAILPSW DC	OD' 0' , X' 0002000180000000' , AD(X' BAD')
00000570	B2B2 8360		00000560	405 FAILTEST LPSWE FAILPSW	Abnormal termination
				407	*****
				408	* Working Storage
				409	*****
00000574	00000000			411 CTLR0 DS F	CRO
00000578	00000000			412	DS F
0000057C				414	LTORG , Literals pool
0000057C	00000080			415	=F' 128'
00000580	00001990			416	=A(E6TESTS)
00000584	00000001			417	=F' 1'
00000588	00000003			418	=XL4' 3'
0000058C	0000			419	=H' 0'
0000058E	005F			420	=AL2(L' MSGMSG)
				421	
				422	* some constants
				423	
	00000400	00000001		424 K EQU 1024	One KB
	00001000	00000001		425 PAGE EQU (4*K)	Size of one page
	00010000	00000001		426 K64 EQU (64*K)	64 KB
	00100000	00000001		427 MB EQU (K*K)	1 MB
				428	
	AABBCCDD	00000001		429 REG2PATT EQU X' AABBCCDD'	Polluted Register pattern
	000000DD	00000001		430 REG2LOW EQU X' DD'	(last byte above)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				432 *=====
				433 *
				434 * NOTE: start data on an address that is easy to display
				435 * within Hercules
				436 *
				437 *=====
				438
00000590		00000590	00001000	439 ORG ZVE6TST+X' 1000'
00001000	00000000			440 FAILED DC F' 0' some test failed?
00001004	00000000			441 TESTING DC F' 0' current test #
				443 *****
				444 * TEST failed : result messgae
				445 *****
				446 *
				447 * failed message and associated editting
				448 *
00001008	40404040	40404040		449 PRTLNE DC C' Test # '
00001018	A7A7A7			450 PRTNUM DC C' xxx'
0000101B	40868189	93858440		451 DC C' failed for instruction '
00001033	A7A7A7A7	A7A7A7A7		452 PRTNAME DC CL8' xxxxxxxx'
0000103B	40A689A3	884089F4		453 DC C' with i4='
00001044	A7A7A7			454 PRTI4 DC C' xxx'
00001047	6B			455 DC C' ,'
00001048	40A689A3	884094F5		456 DC C' with m5='
00001051	A7A7			457 PRTM5 DC C' xx'
00001053	4B			458 DC C' .'
		0000004C	00000001	459 PRTLNG EQU *- PRTLNE
				461 *****
				462 * TEST failed : CC message
				463 *****
				464 *
				465 * failed message and associated editting
				466 *
00001054	40404040	40404040		467 CCPRTLNE DC C' Test # '
00001064	A7A7A7			468 CCPRTNUM DC C' xxx'
00001067	40A69996	95874083		469 DC c' wrong cc for instruction '
00001081	A7A7A7A7	A7A7A7A7		470 CCPRTNAME DC CL8' xxxxxxxx'
00001089	4085A797	8583A385		471 DC C' expected: cc='
00001097	A7			472 CCPRTEXP DC C' x'
00001098	6B			473 DC C' ,'
00001099	40998583	8589A585		474 DC C' received: cc='
000010A7	A7			475 CCPRTGOT DC C' x'
000010A8	4B			476 DC C' .'
		00000055	00000001	477 CCPRTLNG EQU *- CCPRTLNE
				478

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				535 *****
				536 * Macros to help build test tables
				537 *-----
				538 * VRI_F Macro to help build test tables
				539 *****
				540 MACRO
				541 VRI_F &INST, &I4, &M5, &CC
				542 . * &INST - VRI-f instruction under test
				543 . * &i4 - i4 field
				544 . * &m5 - m5 field
				545 . * &CC - expected CC
				546 . *
				547 LCLA &XCC(4) &CC has mask values for FAILED condition codes
				548 &XCC(1) SETA 7 CC != 0
				549 &XCC(2) SETA 11 CC != 1
				550 &XCC(3) SETA 13 CC != 2
				551 &XCC(4) SETA 14 CC != 3
				552
				553 GBLA &TNUM
				554 &TNUM SETA &TNUM+1
				555
				556 DS OFD
				557 USING *, R5 base for test data and test routine
				558
				559 T&TNUM DC A(X&TNUM) address of test routine
				560 DC H' &TNUM test number
				561 DC X' 00'
				562 DC HL1' &I4' i4
				563 DC HL1' &M5' m5
				564 DC HL1' &CC' cc
				565 DC HL1' &XCC(&CC+1)' cc failed mask
				566 V2_&TNUM DC A(RE&TNUM+16) address of v2: 16-byte zoned decimal
				567 V3_&TNUM DC A(RE&TNUM+32) address of v3: 16-byte zoned decimal
				568 DC CL8' &INST' instruction name
				569 DC A(16) result length
				570 REA&TNUM DC A(RE&TNUM) result address
				571 . *
				572 * INSTRUCTION UNDER TEST ROUTINE
				573 X&TNUM DS OF
				574 L R2, V2_&TNUM get v2
				575 VL V2, 0(R2)
				576
				577 L R2, V3_&TNUM get v3
				578 VL V3, 0(R2)
				579
				580 &INST V1, V2, V3, &I4, &M5 test instruction
				581
				582 VST V1, V10OUTPUT save result
				583 EPSW R2, R0 exptrect psw
				584 ST R2, CCPSW to save CC
				585 BR R11 return
				586
				587 RE&TNUM DC OF
				588 DROP R5
				589
				590 MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
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592 *****

593 * **PTTABLE** Macro to generate table of pointers to individual tests

594 *****

595

596 MACRO

597 **PTTABLE**

598 **GBLA &TNUM**

599 LCLA & CUR

600	&CUR	SETA	1
-----	------	------	---

601 . *

602 TTABLE DS OF

603 . LOOP ANOP

604 . *

605	DC	A(T&CUR)	address of test
-----	----	----------	-----------------

606 . *

607 **&CUR** **SETA** **&CUR+1**

```

608      AIF  (&CUR LE &TNUM) . LOOP

```

609 *

610	DC	A(0)	END OF TABLE
-----	----	------	--------------

611 **DC** **A(0)**

612 . *

613 MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				615 *****	
				616 * E6 VRI_F tests	
				617 *****	
00001188		00000000	000019DF	618 ZVE6TST CSECT ,	
				619 DS 0F	
				621 PRINT DATA	
				622 *	
				623 * E670 VPKZR - VECTOR PACK ZONED REGISTER	
				624 *	
				625 * VRI_F instr,i4,m5,cc	
				626 * followed by	
				627 * v1 - 16 byte expected result	
				628 * v2 - 16 byte zoned decimal (operand)	
				629 * v3 - 16 byte zoned decimal (operand)	
				630	
				631 * -----	
				632 * VPKZR - VECTOR PACK ZONED REGISTER	
				633 * -----	
				634 * VPKZR simple + CC checks	
				635 *	i4=129(iom=1 & rdc=1)
				636 *	i4=132(iom=1 & rdc=4)
				637 *	i4=135(iom=1 & rdc=7)
				638 *	i4=142(iom=1 & rdc=14)
				639 *	i4=159(iom=1 & rdc=31)
00001188				640 VRI_F VPKZR, 159, 1, 2	
00001188		00001188		641+ DS 0FD	
00001188	000011AC			642+ USING *,R5	base for test data and test routine
0000118C	0001			643+T1 DC A(X1)	address of test routine
0000118E	00			644+ DC H' 1'	test number
0000118F	9F			645+ DC X' 00'	
00001190	01			646+ DC HL1' 159'	i4
00001191	02			647+ DC HL1' 1'	m5
00001192	0D			648+ DC HL1' 2'	cc
00001194	000011E8			649+ DC HL1' 13'	cc failed mask
00001198	000011F8			650+V2_1 DC A(RE1+16)	address of v2: 16-byte zoned decimal
0000119C	E5D7D2E9 D9404040			651+V3_1 DC A(RE1+32)	address of v3: 16-byte zoned decimal
000011A4	00000010			652+ DC CL8' VPKZR'	instruction name
000011A8	000011D8			653+ DC A(16)	result length
				654+REA1 DC A(RE1)	result address
				655+*	INSTRUCTION UNDER TEST ROUTINE
000011AC				656+X1 DS 0F	
000011AC	5820 500C		00001194	657+ L R2, V2_1	get v2
000011B0	E722 0000 0006		00000000	658+ VL V2, 0(R2)	
000011B6	5820 5010		00001198	659+ L R2, V3_1	get v3
000011BA	E732 0000 0006		00000000	660+ VL V3, 0(R2)	
000011C0	E612 3019 F070			661+ VPKZR V1, V2, V3, 159, 1	test instruction
000011C6	E710 8F08 000E		00001108	662+ VST V1, V10UTPUT	save result
000011CC	B98D 0020			663+ EPSW R2, R0	extract psw
000011D0	5020 8EE8		000010E8	664+ ST R2, CCPSW	to save CC
000011D4	07FB			665+ BR R11	return
000011D8				666+RE1 DC 0F	
000011D8				667+ DROP R5	
000011D8	00000000 00000000			668 DC XL16' 000000000000000000000000000022C'	V1
000011E0	00000000 0000022C				

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000011E8	F0F0F0F0 F0F0F0F0			669	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0'	V2
000011F0	F0F0F0F0 F0F0F0F0						
000011F8	F0F0F0F0 F0F0F0F0			670	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F2C2'	V3
00001200	F0F0F0F0 F0F0F2C2						
				671			
				672	VRI_F	VPKZR, 159, 1, 2	
00001208				673+	DS	OFD	
00001208		00001208		674+	USING	*, R5	base for test data and test routine
00001208	0000122C			675+T2	DC	A(X2)	address of test routine
0000120C	0002			676+	DC	H' 2'	test number
0000120E	00			677+	DC	X' 00'	
0000120F	9F			678+	DC	HL1' 159'	i4
00001210	01			679+	DC	HL1' 1'	m5
00001211	02			680+	DC	HL1' 2'	cc
00001212	0D			681+	DC	HL1' 13'	cc failed mask
00001214	00001268			682+V2_2	DC	A(RE2+16)	address of v2: 16-byte zoned decimal
00001218	00001278			683+V3_2	DC	A(RE2+32)	address of v3: 16-byte zoned decimal
0000121C	E5D7D2E9 D9404040			684+	DC	CL8' VPKZR'	instruction name
00001224	00000010			685+	DC	A(16)	result length
00001228	00001258			686+REA2	DC	A(RE2)	result address
				687+*			INSTRUCTION UNDER TEST ROUTINE
0000122C				688+X2	DS	OF	
0000122C	5820 500C		00001214	689+	L	R2, V2_2	get v2
00001230	E722 0000 0006		00000000	690+	VL	V2, 0(R2)	
00001236	5820 5010		00001218	691+	L	R2, V3_2	get v3
0000123A	E732 0000 0006		00000000	692+	VL	V3, 0(R2)	
00001240	E612 3019 F070			693+	VPKZR	V1, V2, V3, 159, 1	test instruction
00001246	E710 8F08 000E		00001108	694+	VST	V1, V10UTPUT	save result
0000124C	B98D 0020			695+	EPSW	R2, R0	exptract psw
00001250	5020 8EE8		000010E8	696+	ST	R2, CCPSW	to save CC
00001254	07FB			697+	BR	R11	return
00001258				698+RE2	DC	OF	
00001258				699+	DROP	R5	
00001258	12300000 00000000			700	DC	XL16' 12300000000000000000000000000000122C'	V1
00001260	00000000 0000122C						
00001268	F0F1F2F3 F0F0F0F0			701	DC	XL16' F0F1F2F3F0F0F0F0F0F0F0F0F0F0F0F0'	V2
00001270	F0F0F0F0 F0F0F0F0						
00001278	F0F0F0F0 F0F0F0F0			702	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F1F2C2'	V3
00001280	F0F0F0F0 F0F1F2C2						
				703			
				704	VRI_F	VPKZR, 159, 1, 1	
00001288				705+	DS	OFD	
00001288		00001288		706+	USING	*, R5	base for test data and test routine
00001288	000012AC			707+T3	DC	A(X3)	address of test routine
0000128C	0003			708+	DC	H' 3'	test number
0000128E	00			709+	DC	X' 00'	
0000128F	9F			710+	DC	HL1' 159'	i4
00001290	01			711+	DC	HL1' 1'	m5
00001291	01			712+	DC	HL1' 1'	cc
00001292	0B			713+	DC	HL1' 11'	cc failed mask
00001294	000012E8			714+V2_3	DC	A(RE3+16)	address of v2: 16-byte zoned decimal
00001298	000012F8			715+V3_3	DC	A(RE3+32)	address of v3: 16-byte zoned decimal
0000129C	E5D7D2E9 D9404040			716+	DC	CL8' VPKZR'	instruction name
000012A4	00000010			717+	DC	A(16)	result length
000012A8	000012D8			718+REA3	DC	A(RE3)	result address
				719+*			INSTRUCTION UNDER TEST ROUTINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001388		00001388		770+	USING *,R5	base for test data and test routine
00001388	000013AC			771+T5	DC A(X5)	address of test routine
0000138C	0005			772+	DC H' 5'	test number
0000138E	00			773+	DC X' 00'	
0000138F	87			774+	DC HL1' 135'	i4
00001390	01			775+	DC HL1' 1'	m5
00001391	03			776+	DC HL1' 3'	cc
00001392	0E			777+	DC HL1' 14'	cc failed mask
00001394	000013E8			778+V2_5	DC A(RE5+16)	address of v2: 16-byte zoned decimal
00001398	000013F8			779+V3_5	DC A(RE5+32)	address of v3: 16-byte zoned decimal
0000139C	E5D7D2E9 D9404040			780+	DC CL8' VPKZR'	instruction name
000013A4	00000010			781+	DC A(16)	result length
000013A8	000013D8			782+REA5	DC A(RE5)	result address
				783+*		INSTRUCTION UNDER TEST ROUTINE
000013AC				784+X5	DS 0F	
000013AC	5820 500C		00001394	785+	L R2, V2_5	get v2
000013B0	E722 0000 0006		00000000	786+	VL V2, 0(R2)	
000013B6	5820 5010		00001398	787+	L R2, V3_5	get v3
000013BA	E732 0000 0006		00000000	788+	VL V3, 0(R2)	
000013C0	E612 3018 7070			789+	VPKZR V1, V2, V3, 135, 1	test instruction
000013C6	E710 8F08 000E		00001108	790+	VST V1, V10UTPUT	save result
000013CC	B98D 0020			791+	EPSW R2, R0	exptract psw
000013D0	5020 8EE8		000010E8	792+	ST R2, CCPSW	to save CC
000013D4	07FB			793+	BR R11	return
000013D8				794+RE5	DC 0F	
000013D8				795+	DROP R5	
000013D8	00000000 00000000			796	DC XL16' 0000000000000000000000000000123D'	V1
000013E0	00000000 0000123D					
000013E8	F0F9F8F7 F0F0F0F0			797	DC XL16' F0F9F8F7F0F0F0F0F0F0F0F0F0F0F0F0'	V2
000013F0	F0F0F0F0 F0F0F0F0					
000013F8	F0F0F0F0 F0F0F0F0			798	DC XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F1F2D3'	V3
00001400	F0F0F0F0 F0F1F2D3					
				799		
				800	VRI_F VPKZR, 135, 1, 3	(overflow; rdc=7)
00001408				801+	DS 0FD	
00001408		00001408		802+	USING *,R5	base for test data and test routine
00001408	0000142C			803+T6	DC A(X6)	address of test routine
0000140C	0006			804+	DC H' 6'	test number
0000140E	00			805+	DC X' 00'	
0000140F	87			806+	DC HL1' 135'	i4
00001410	01			807+	DC HL1' 1'	m5
00001411	03			808+	DC HL1' 3'	cc
00001412	0E			809+	DC HL1' 14'	cc failed mask
00001414	00001468			810+V2_6	DC A(RE6+16)	address of v2: 16-byte zoned decimal
00001418	00001478			811+V3_6	DC A(RE6+32)	address of v3: 16-byte zoned decimal
0000141C	E5D7D2E9 D9404040			812+	DC CL8' VPKZR'	instruction name
00001424	00000010			813+	DC A(16)	result length
00001428	00001458			814+REA6	DC A(RE6)	result address
				815+*		INSTRUCTION UNDER TEST ROUTINE
0000142C				816+X6	DS 0F	
0000142C	5820 500C		00001414	817+	L R2, V2_6	get v2
00001430	E722 0000 0006		00000000	818+	VL V2, 0(R2)	
00001436	5820 5010		00001418	819+	L R2, V3_6	get v3
0000143A	E732 0000 0006		00000000	820+	VL V3, 0(R2)	
00001440	E612 3018 7070			821+	VPKZR V1, V2, V3, 135, 1	test instruction
00001446	E710 8F08 000E		00001108	822+	VST V1, V10UTPUT	save result

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000144C	B98D 0020			823+	EPSW	R2, R0	exptract psw
00001450	5020 8EE8		000010E8	824+	ST	R2, CCPSW	to save CC
00001454	07FB			825+	BR	R11	return
00001458				826+RE6	DC	0F	
00001458				827+	DROP	R5	
00001458	00000000 00000000			828	DC	XL16' 0000000000000000000000000000123D'	V1
00001460	00000000 0000123D						
00001468	F0F0F0F0 F0F0F0F0			829	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0'	V2
00001470	F0F0F0F0 F0F0F0F0						
00001478	F0F0F0F0 F0F0F0F0			830	DC	XL16' F0F0F0F0F0F0F0F0F0F0F9F0F0F0F0F1F2D3'	V3
00001480	F9F0F0F0 F0F1F2D3						
				831			
00001488				832	VRI_F	VPKZR, 142, 1, 3	(overflow; rdc=14)
00001488		00001488		833+	DS	0FD	
00001488	000014AC			834+	USING	*, R5	base for test data and test routine
0000148C	0007			835+T7	DC	A(X7)	address of test routine
0000148E	00			836+	DC	H' 7'	test number
0000148F	8E			837+	DC	X' 00'	
00001490	01			838+	DC	HL1' 142'	i4
00001491	03			839+	DC	HL1' 1'	m5
00001492	0E			840+	DC	HL1' 3'	cc
00001494	000014E8			841+	DC	HL1' 14'	cc failed mask
00001498	000014F8			842+V2_7	DC	A(RE7+16)	address of v2: 16-byte zoned decimal
0000149C	E5D7D2E9 D9404040			843+V3_7	DC	A(RE7+32)	address of v3: 16-byte zoned decimal
000014A4	00000010			844+	DC	CL8' VPKZR'	instruction name
000014A8	000014D8			845+	DC	A(16)	result length
				846+REA7	DC	A(RE7)	result address
				847+*			INSTRUCTION UNDER TEST ROUTINE
000014AC				848+X7	DS	0F	
000014AC	5820 500C		00001494	849+	L	R2, V2_7	get v2
000014B0	E722 0000 0006		00000000	850+	VL	V2, 0(R2)	
000014B6	5820 5010		00001498	851+	L	R2, V3_7	get v3
000014BA	E732 0000 0006		00000000	852+	VL	V3, 0(R2)	
000014C0	E612 3018 E070			853+	VPKZR	V1, V2, V3, 142, 1	test instruction
000014C6	E710 8F08 000E		00001108	854+	VST	V1, V10UTPUT	save result
000014CC	B98D 0020			855+	EPSW	R2, R0	exptract psw
000014D0	5020 8EE8		000010E8	856+	ST	R2, CCPSW	to save CC
000014D4	07FB			857+	BR	R11	return
000014D8				858+RE7	DC	0F	
000014D8				859+	DROP	R5	
000014D8	00000000 00000000			860	DC	XL16' 00000000000000000000000090000123D'	V1
000014E0	00000009 0000123D						
000014E8	F0F0F0F0 F0F0F0F0			861	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F9'	V2
000014F0	F0F0F0F0 F0F0F0F9						
000014F8	F0F0F0F0 F0F0F0F0			862	DC	XL16' F0F0F0F0F0F0F0F0F0F0F9F0F0F0F0F1F2D3'	V3
00001500	F9F0F0F0 F0F1F2D3						
				863			
				864	* m5 tests (note: cs is always 1)		
				865	*	m5=1	(nsv=0, nv=0, p1=0, cs=1)
				866	*	m5=3	(nsv=0, nv=0, p1=1, cs=1)
				867	*	m5=5	(nsv=0, nv=1, p1=0, cs=1)
				868	*	m5=7	(nsv=0, nv=1, p1=1, cs=1)
				869	*	m5=9	(nsv=1, nv=0, p1=0, cs=1)
				870	*	m5=11	(nsv=1, nv=0, p1=1, cs=1)
				871	*	m5=13	(nsv=1, nv=1, p1=0, cs=1)
				872	*	m5=15	(nsv=1, nv=1, p1=1, cs=1)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				873		
				874	VRI_F VPKZR, 159, 3, 2	
00001508				875+	DS OFD	
00001508		00001508		876+	USING *, R5	base for test data and test routine
00001508	0000152C			877+T8	DC A(X8)	address of test routine
0000150C	0008			878+	DC H' 8'	test number
0000150E	00			879+	DC X' 00'	
0000150F	9F			880+	DC HL1' 159'	i4
00001510	03			881+	DC HL1' 3'	m5
00001511	02			882+	DC HL1' 2'	cc
00001512	0D			883+	DC HL1' 13'	cc failed mask
00001514	00001568			884+V2_8	DC A(RE8+16)	address of v2: 16-byte zoned decimal
00001518	00001578			885+V3_8	DC A(RE8+32)	address of v3: 16-byte zoned decimal
0000151C	E5D7D2E9 D9404040			886+	DC CL8' VPKZR'	instruction name
00001524	00000010			887+	DC A(16)	result length
00001528	00001558			888+REA8	DC A(RE8)	result address
				889+*		INSTRUCTION UNDER TEST ROUTINE
0000152C				890+X8	DS OF	
0000152C	5820 500C		00001514	891+	L R2, V2_8	get v2
00001530	E722 0000 0006		00000000	892+	VL V2, 0(R2)	
00001536	5820 5010		00001518	893+	L R2, V3_8	get v3
0000153A	E732 0000 0006		00000000	894+	VL V3, 0(R2)	
00001540	E612 3039 F070			895+	VPKZR V1, V2, V3, 159, 3	test instruction
00001546	E710 8F08 000E		00001108	896+	VST V1, V10UTPUT	save result
0000154C	B98D 0020			897+	EPSW R2, R0	exptract psw
00001550	5020 8EE8		000010E8	898+	ST R2, CCPSW	to save CC
00001554	07FB			899+	BR R11	return
00001558				900+RE8	DC OF	
00001558				901+	DROP R5	
00001558	00000000 00000000			902	DC XL16' 0000000000000000000000000000000022F'	V1
00001560	00000000 0000022F					
00001568	F0F0F0F0 F0F0F0F0			903	DC XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0'	V2
00001570	F0F0F0F0 F0F0F0F0					
00001578	F0F0F0F0 F0F0F0F0			904	DC XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F2C2'	V3
00001580	F0F0F0F0 F0F0F2C2					
				905		
				906	VRI_F VPKZR, 159, 3, 2	p1=1
00001588				907+	DS OFD	
00001588		00001588		908+	USING *, R5	base for test data and test routine
00001588	000015AC			909+T9	DC A(X9)	address of test routine
0000158C	0009			910+	DC H' 9'	test number
0000158E	00			911+	DC X' 00'	
0000158F	9F			912+	DC HL1' 159'	i4
00001590	03			913+	DC HL1' 3'	m5
00001591	02			914+	DC HL1' 2'	cc
00001592	0D			915+	DC HL1' 13'	cc failed mask
00001594	000015E8			916+V2_9	DC A(RE9+16)	address of v2: 16-byte zoned decimal
00001598	000015F8			917+V3_9	DC A(RE9+32)	address of v3: 16-byte zoned decimal
0000159C	E5D7D2E9 D9404040			918+	DC CL8' VPKZR'	instruction name
000015A4	00000010			919+	DC A(16)	result length
000015A8	000015D8			920+REA9	DC A(RE9)	result address
				921+*		INSTRUCTION UNDER TEST ROUTINE
000015AC				922+X9	DS OF	
000015AC	5820 500C		00001594	923+	L R2, V2_9	get v2
000015B0	E722 0000 0006		00000000	924+	VL V2, 0(R2)	
000015B6	5820 5010		00001598	925+	L R2, V3_9	get v3

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
000015BA	E732 0000 0006		00000000	926+	VL	V3, 0(R2)		
000015C0	E612 3039 F070			927+	VPKZR	V1, V2, V3, 159, 3	test instruction	
000015C6	E710 8F08 000E		00001108	928+	VST	V1, V10UTPUT	save result	
000015CC	B98D 0020			929+	EPSW	R2, R0	exptract psw	
000015D0	5020 8EE8		000010E8	930+	ST	R2, CCPSW	to save CC	
000015D4	07FB			931+	BR	R11	return	
000015D8				932+RE9	DC	0F		
000015D8				933+	DROP	R5		
000015D8	98700000 00000000			934	DC	XL16' 98700000000000000000000000000000123F'	V1	
000015E0	00000000 0000123F							
000015E8	F0F9F8F7 F0F0F0F0			935	DC	XL16' F0F9F8F7F0F0F0F0F0F0F0F0F0F0F0F0F0F0'	V2	
000015F0	F0F0F0F0 F0F0F0F0							
000015F8	F0F0F0F0 F0F0F0F0			936	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F1F2D3'	V3	
00001600	F0F0F0F0 F0F1F2D3							
				937				
				938	VRI_F	VPKZR, 159, 5, 3	nv=1 & invalid sign	
00001608				939+	DS	0FD		
00001608		00001608		940+	USING	*, R5	base for test data and test routine	
00001608	0000162C			941+T10	DC	A(X10)	address of test routine	
0000160C	000A			942+	DC	H' 10'	test number	
0000160E	00			943+	DC	X' 00'		
0000160F	9F			944+	DC	HL1' 159'	i4	
00001610	05			945+	DC	HL1' 5'	m5	
00001611	03			946+	DC	HL1' 3'	cc	
00001612	0E			947+	DC	HL1' 14'	cc failed mask	
00001614	00001668			948+V2_10	DC	A(RE10+16)	address of v2: 16-byte zoned decimal	
00001618	00001678			949+V3_10	DC	A(RE10+32)	address of v3: 16-byte zoned decimal	
0000161C	E5D7D2E9 D9404040			950+	DC	CL8' VPKZR'	instruction name	
00001624	00000010			951+	DC	A(16)	result length	
00001628	00001658			952+REA10	DC	A(RE10)	result address	
				953+*			INSTRUCTION UNDER TEST ROUTINE	
0000162C				954+X10	DS	0F		
0000162C	5820 500C		00001614	955+	L	R2, V2_10	get v2	
00001630	E722 0000 0006		00000000	956+	VL	V2, 0(R2)		
00001636	5820 5010		00001618	957+	L	R2, V3_10	get v3	
0000163A	E732 0000 0006		00000000	958+	VL	V3, 0(R2)		
00001640	E612 3059 F070			959+	VPKZR	V1, V2, V3, 159, 5	test instruction	
00001646	E710 8F08 000E		00001108	960+	VST	V1, V10UTPUT	save result	
0000164C	B98D 0020			961+	EPSW	R2, R0	exptract psw	
00001650	5020 8EE8		000010E8	962+	ST	R2, CCPSW	to save CC	
00001654	07FB			963+	BR	R11	return	
00001658				964+RE10	DC	0F		
00001658				965+	DROP	R5		
00001658	00000000 00000000			966	DC	XL16' 00000000000000000000000000000000229'	V1	
00001660	00000000 00000229							
00001668	F0F0F0F0 F0F0F0F0			967	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0'	V2	
00001670	F0F0F0F0 F0F0F0F0							
00001678	F0F0F0F0 F0F0F0F0			968	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F292'	V3	
00001680	F0F0F0F0 F0F0F292							
				969				
				970	VRI_F	VPKZR, 159, 5, 3	nv=1 & invalid digit	
00001688				971+	DS	0FD		
00001688		00001688		972+	USING	*, R5	base for test data and test routine	
00001688	000016AC			973+T11	DC	A(X11)	address of test routine	
0000168C	000B			974+	DC	H' 11'	test number	
0000168E	00			975+	DC	X' 00'		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000168F	9F			976+	DC	HL1' 159'	i4
00001690	05			977+	DC	HL1' 5'	m5
00001691	03			978+	DC	HL1' 3'	cc
00001692	0E			979+	DC	HL1' 14'	cc failed mask
00001694	000016E8			980+V2_11	DC	A(RE11+16)	address of v2: 16-byte zoned decimal
00001698	000016F8			981+V3_11	DC	A(RE11+32)	address of v3: 16-byte zoned decimal
0000169C	E5D7D2E9 D9404040			982+	DC	CL8' VPKZR'	instruction name
000016A4	00000010			983+	DC	A(16)	result length
000016A8	000016D8			984+REA11	DC	A(RE11)	result address
				985+*			INSTRUCTION UNDER TEST ROUTINE
000016AC				986+X11	DS	0F	
000016AC	5820 500C		00001694	987+	L	R2, V2_11	get v2
000016B0	E722 0000 0006		00000000	988+	VL	V2, 0(R2)	
000016B6	5820 5010		00001698	989+	L	R2, V3_11	get v3
000016BA	E732 0000 0006		00000000	990+	VL	V3, 0(R2)	
000016C0	E612 3059 F070			991+	VPKZR	V1, V2, V3, 159, 5	test instruction
000016C6	E710 8F08 000E		00001108	992+	VST	V1, V10UTPUT	save result
000016CC	B98D 0020			993+	EPSW	R2, R0	exptract psw
000016D0	5020 8EE8		000010E8	994+	ST	R2, CCPSW	to save CC
000016D4	07FB			995+	BR	R11	return
000016D8				996+RE11	DC	0F	
000016D8				997+	DROP	R5	
000016D8	F0000000 00000000			998	DC	XL16' F00000000000000000000000000000229'	V1
000016E0	00000000 00000229						
000016E8	F0FFF0F0 F0F0F0F0			999	DC	XL16' F0FFF0F0F0F0F0F0F0F0F0F0F0F0F0F0'	V2
000016F0	F0F0F0F0 F0F0F0F0						
000016F8	F0F0F0F0 F0F0F0F0			1000	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F292'	V3
00001700	F0F0F0F0 F0F0F292						
				1001			
				1002	VRI_F	VPKZR, 159, 7, 3	nv=1, p1=1 & invalid digit
00001708				1003+	DS	0FD	
00001708		00001708		1004+	USING	*, R5	base for test data and test routine
00001708	0000172C			1005+T12	DC	A(X12)	address of test routine
0000170C	000C			1006+	DC	H' 12'	test number
0000170E	00			1007+	DC	X' 00'	
0000170F	9F			1008+	DC	HL1' 159'	i4
00001710	07			1009+	DC	HL1' 7'	m5
00001711	03			1010+	DC	HL1' 3'	cc
00001712	0E			1011+	DC	HL1' 14'	cc failed mask
00001714	00001768			1012+V2_12	DC	A(RE12+16)	address of v2: 16-byte zoned decimal
00001718	00001778			1013+V3_12	DC	A(RE12+32)	address of v3: 16-byte zoned decimal
0000171C	E5D7D2E9 D9404040			1014+	DC	CL8' VPKZR'	instruction name
00001724	00000010			1015+	DC	A(16)	result length
00001728	00001758			1016+REA12	DC	A(RE12)	result address
				1017+*			INSTRUCTION UNDER TEST ROUTINE
0000172C				1018+X12	DS	0F	
0000172C	5820 500C		00001714	1019+	L	R2, V2_12	get v2
00001730	E722 0000 0006		00000000	1020+	VL	V2, 0(R2)	
00001736	5820 5010		00001718	1021+	L	R2, V3_12	get v3
0000173A	E732 0000 0006		00000000	1022+	VL	V3, 0(R2)	
00001740	E612 3079 F070			1023+	VPKZR	V1, V2, V3, 159, 7	test instruction
00001746	E710 8F08 000E		00001108	1024+	VST	V1, V10UTPUT	save result
0000174C	B98D 0020			1025+	EPSW	R2, R0	exptract psw
00001750	5020 8EE8		000010E8	1026+	ST	R2, CCPSW	to save CC
00001754	07FB			1027+	BR	R11	return
00001758				1028+RE12	DC	0F	

[illegible]

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
000019C0	00001788			1182+	DC A(T13) address of test
000019C4	00001808			1183+	DC A(T14) address of test
000019C8	00001888			1184+	DC A(T15) address of test
000019CC	00001908			1185+	DC A(T16) address of test
				1186+*	
000019D0	00000000			1187+	DC A(0) END OF TABLE
000019D4	00000000			1188+	DC A(0)
				1189	
000019D8	00000000			1190	DC F' 0' END OF TABLE
000019DC	00000000			1191	DC F' 0'

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				1193 *****	
				1194 * Register equates	
				1195 *****	
		00000000	00000001	1197 R0	EQU 0
		00000001	00000001	1198 R1	EQU 1
		00000002	00000001	1199 R2	EQU 2
		00000003	00000001	1200 R3	EQU 3
		00000004	00000001	1201 R4	EQU 4
		00000005	00000001	1202 R5	EQU 5
		00000006	00000001	1203 R6	EQU 6
		00000007	00000001	1204 R7	EQU 7
		00000008	00000001	1205 R8	EQU 8
		00000009	00000001	1206 R9	EQU 9
		0000000A	00000001	1207 R10	EQU 10
		0000000B	00000001	1208 R11	EQU 11
		0000000C	00000001	1209 R12	EQU 12
		0000000D	00000001	1210 R13	EQU 13
		0000000E	00000001	1211 R14	EQU 14
		0000000F	00000001	1212 R15	EQU 15
				1214 *****	
				1215 * Register equates	
				1216 *****	
		00000000	00000001	1218 V0	EQU 0
		00000001	00000001	1219 V1	EQU 1
		00000002	00000001	1220 V2	EQU 2
		00000003	00000001	1221 V3	EQU 3
		00000004	00000001	1222 V4	EQU 4
		00000005	00000001	1223 V5	EQU 5
		00000006	00000001	1224 V6	EQU 6
		00000007	00000001	1225 V7	EQU 7
		00000008	00000001	1226 V8	EQU 8
		00000009	00000001	1227 V9	EQU 9
		0000000A	00000001	1228 V10	EQU 10
		0000000B	00000001	1229 V11	EQU 11
		0000000C	00000001	1230 V12	EQU 12
		0000000D	00000001	1231 V13	EQU 13
		0000000E	00000001	1232 V14	EQU 14
		0000000F	00000001	1233 V15	EQU 15
		00000010	00000001	1234 V16	EQU 16
		00000011	00000001	1235 V17	EQU 17
		00000012	00000001	1236 V18	EQU 18
		00000013	00000001	1237 V19	EQU 19
		00000014	00000001	1238 V20	EQU 20
		00000015	00000001	1239 V21	EQU 21

DESC	SYMBOL	SIZE	POS	ADDR
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Entry: 0

Image	IMAGE	6624	0000- 19DF	0000- 19DF
Regi on		6624	0000- 19DF	0000- 19DF
CSECT	ZVE6TST	6624	0000- 19DF	0000- 19DF

STMT	FILE NAME
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1	/home/tn529/sharedvfp/tests/zvector-e6-06-VPKZR.asm
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**** NO ERRORS FOUND ****